

Notice of References Cited	Application/Control No. 10/659,593		Applicant(s)/Patent Under Reexamination LEE, BAEK-WOON	
	Examiner Stephen G. Sherman		Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,542,212	04-2003	Yoshida et al.	349/141
	B	US-			
	C	US-			
	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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